


Search Notes 	Application/Control No. 10616525	Applicant(s)/Patent Under Reexamination FUNK ET AL.
	Examiner Rutten, J. Derek	Art Unit 2192

SEARCHED			
Class	Subclass	Date	Examiner

SEARCH NOTES		
Search Notes	Date	Examiner
717/127-130; 714/34,35 (Updated text search - see search history printout)	7/6/07	/jdr/
EAST (US-PGPUB; USPAT; EPO; JPO; IBM_TDB; DERWENT - see search history printout)	7/6/07	/jdr/
Tuan Dam, SPE 2192 and Wei Zhen, SPE 2191 (appeal conference)	5/16/08	/jdr/

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner